

Notice of References Cited	Application/Control No. 10/077,668	Applicant(s)/Patent Under Reexamination FRANK, SIMON	
	Examiner Kiran B. Patel	Art Unit 3612	Page 1 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
<input checked="" type="checkbox"/>	A	US-3,842,222	10-1974	Hogland, Keith C.	293/133
<input type="checkbox"/>	B	US-3,897,095	07-1975	Glance et al.	293/120
<input type="checkbox"/>	C	US-3,912,295	10-1975	Eggert, Jr., Walter S.	293/133
<input type="checkbox"/>	D	US-3,998,485	12-1976	Putter et al.	293/133
<input type="checkbox"/>	E	US-4,023,652	05-1977	Torke, Gernot	293/133
<input type="checkbox"/>	F	US-4,272,114	06-1981	Hirano et al.	293/133
<input type="checkbox"/>	G	US-4,413,856	11-1983	McMahan et al.	293/120
<input type="checkbox"/>	H	US-4,465,312	08-1984	Werner, Lawrence E.	293/133
<input type="checkbox"/>	I	US-4,684,151	08-1987	Drewek, David F.	296/189
<input type="checkbox"/>	J	US-5,078,439	01-1992	Terada et al.	293/122
<input type="checkbox"/>	K	US-5,201,912	04-1993	Terada et al.	293/133
<input type="checkbox"/>	L	US-5,314,229	05-1994	Matuzawa et al.	293/133
<input type="checkbox"/>	M	US-5,403,049	04-1995	Ebbinghaus, Alfred	293/133

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
<input checked="" type="checkbox"/>	N	JP2-175452	07-1990	JAPAN		
<input type="checkbox"/>	O	DE19517921	11-1996	GERMANY		
<input type="checkbox"/>	P	EP0854066	12-1997	EUROPEAN		
<input type="checkbox"/>	Q	DE19700022	07-1998	GERMAN		
<input type="checkbox"/>	R	JP11-268663	10-1999	JAPAN		
<input type="checkbox"/>	S	DE19913078	09-2000	GERMAN		
<input type="checkbox"/>	T	JP2002-104107	04-2002	JAPAN		

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
<input type="checkbox"/>	U	
<input type="checkbox"/>	V	
<input type="checkbox"/>	W	
<input type="checkbox"/>	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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3612

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
K99	A	US-5,431,445	07-1995	Wheatley, Donald G.	296/189
	B	US-5,732,801	03-1998	Gertz, David C.	293/133
	C	US-5,772,267	06-1998	Heim et al.	293/133
	D	US-5,853,195	12-1998	Le et al.	296/189
	E	US-5,876,078	03-1999	Miskech et al.	293/133
	F	US-6,106,039	08-2000	Maki, Tetsuo	293/133
	G	US-6,203,098	03-2001	Motozawa et al.	293/133
	H	US-6,152,521	11-2000	Hayashi et al.	296/188
	I	US-6,174,009	01-2001	McKeon, R. Clayton	293/133
	J	US-6,179,355	01-2001	Chou et al.	293/133
	K	US-6,227,582	05-2001	Ichien, Takamitsu	293/133
	L	US-6,299,226	10-2001	Kroning et al.	293/120
	M	US-2001/0013706	08-2001	Artner, Bernd	293/133

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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